

SiC Schottky Barrier Diode

SN0610G4

 $V_{RRM} = 650 \text{ V}$ $I_F(T_C=150^{\circ}\text{C}) = 10 \text{ A}$ $Q_C = 24 \text{ nC}$

Features

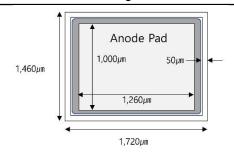
Silicon Carbide Schottky Barrier Diode

Small Die Size

Low I_{R}

High-Recovery Speed

Die Structure & Pattern Diagram



Applications

Switch Mode Power Supplies Power Factor Correction Secondary Side Rectification PV Power Conditioners

Chip Information

Wafer size	6 inch
Chip size	1,460 * 1,720µm
Chip thickness	$350 \mu \text{m}$
Scribe line width	$100 \mu \text{m}$
Pad diameter	1,000 * 1,260µm
Top metallization	AlCu(Cu 0.5%) for Wire
Back metallization	Ti-Ni-Ag (for Solder)
Chip quantity	5,844 pcs/wafer

Maximum Ratings (T_a = 25°C)

Parameter	Symbol	Conditions	Limit	Unit
Repetitive peak reverse voltage	V_{RM}		650	V
Reverse voltage (DC)	V_{R}		650	V
Forward voltage (DC)	I_{F}		10	Α
Peak surge forward current	I_{FSM}	10 ms Sinusoidal	70	Α
Junction temperature	T_{j}		175	°C
Storage temperature	T_{stg}		-55 to +175	°C

Electrical Characteristics (T_a = 25°C)

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Parameter	Symbol	Conditions	Min	Тур	Max	Unit
DC blocking voltage	V_{DC}	I _R = 30 μA	650	-	-	V
Forward voltage	VF	I _F = 8A, Ta = 25°C	-	1.36	1.70	V
		I _F = 8A, Ta = 150°C	-	1.64	-	V
		I _F = 8A, Ta = 175°C	-	1.73	-	V
Reverse current	I_R	V _R = 650V, Ta = 25°C	-	0.7	50	μΑ
		V _R = 650V, Ta = 150°C	-	7	-	μΑ
		V _R = 650V, Ta = 175°C	-	12	-	μΑ
Total capacitance	С	$V_R = 1V$, $f = 1MHz$	-	329	-	pF
Total capacitive charge	Q_{C}	$V_R = 400V$, di/dt = 350 A/ μ s	-	24	-	nC
Switching time	Tc	$V_R = 400V$, di/dt = 350 A/ μ s	-	15	-	ns

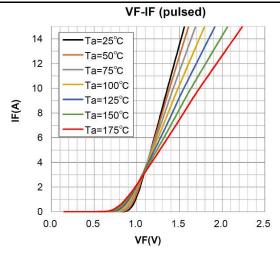


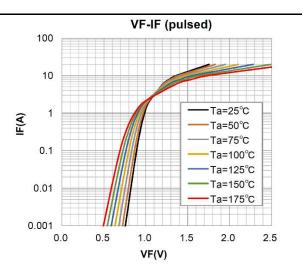
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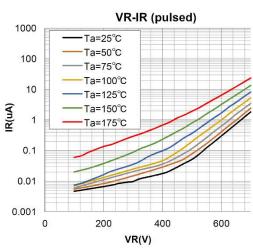
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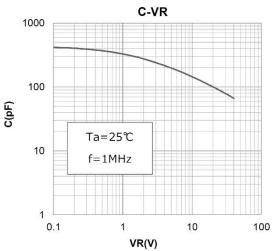
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Electrical characteristic curves











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Notes

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- 2. Please request for the specification sheet before use.
- 3. Since the products are in wafer form, the values in this document are for reference only.
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